

Date Created : 2009/08/05  
Date Issued On : 2009/09/14  
PCN# : Q3093201

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

Technical Contact:  
Name: Lee, JongChan  
E-mail: jongchan.lee@fairchildsemi.com  
Phone: 82-32-680-1846

PCN Originator:  
Name: Lee, JongChan  
E-mail: jongchan.lee@fairchildsemi.com  
Phone: 82-32-680-1846

Implementation of change:  
Expected 1st Device Shipment Date: 2009/11/26

Earliest Year/Work Week of Changed Product: 0948

Change Type Description: Fab Process Change

Description of Change (From): 4um/40V fab process in Bucheon, Korea.

Description of Change (To): 1.5um/40V fab process in Bucheon, Korea. Functionality and electrical characteristics remain within current datasheet specifications.

Reason for Change : Product availability and manufacturing flexibility.

Qual/REL Plan Numbers : Q20080261

Qualification :

The product qualification of process change for LM78XX series which is derived from the same wafer with KA78XX series has successfully completed, allowing release of the affected product list.

**Results/Discussion for Qual Plan Number Q20080261**

Test: (Charged Device Model ESD)   Conditions: 1000V   Standard: JESD22-C101					
Lot	Device	Results		Failure Code	
Q20080261AACDM	LM7805ACT	0/3			

  

Test: (High Temperature Op Life)   Conditions: 125C   Standard:					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20080261AAHTOL	LM7805ACT	0/77			
			0/77		
				0/77	

Test: (High Temperature Storage Life)   Conditions: 150C   Standard: JESD22-A103					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20080261AAHTSL		0/77			
			0/77		
				0/77	

  

Test: (Human Body Model ESD)   Conditions: 2000V   Standard: JESD22-A114			
Lot	Device	Results	Failure Code
Q20080261AAHBM	LM7805ACT	0/3	

  

Test: (Temperature Cycle)   Conditions: -65C, 150C   Standard: JESD22-A104				
Lot	Device	100-CYCLES	500-CYCLES	Failure Code
Q20080261AATMCL1	LM7805ACT	0/77		
Q20080261AATMCL1	LM7805ACT		0/77	

  

Test: (Temperature Humidity Biased Test)   Conditions: 85%RH, 85C, 7V   Standard: JESD22-A101					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20080261AATHBT		0/77			
			0/77		
				0/77	

Product Id Description : Regulator

Affected FSIDs :

KA7805AETU	KA7805ETU	KA7806AETU
KA7806ETU	KA7808ETU	KA7809AETU
KA7809ETU	KA7810AETU	KA7810ETU
KA7812ETU	KA7815ETU	KA7818ETU
KA7824ETU		